

Super FAP-E^{3S} Low Qg series

N-Channel enhancement mode power MOSFET

■ Features

Low on-state resistance
Low switching loss
easy to use
(more controllable switching dV/dt by Rg)
The reliability trial conforms to AEC Q101.
100% avalanche tested

■ Applications

Automotive switching applications

■ Absolute Maximum Ratings at Tc=25°C(unless otherwise specified)

Description	Symbol	Characteristics	Unit	Remarks
Drain-Source Voltage	V _{DS}	600	V	
	V _{DSX}	600	V	V _{GS} =-30V
Continuous Drain Current	I _D	±36	A	
Pulsed Drain Current	I _{DP}	±144	A	
Gate-Source Voltage	V _{GS}	±30	V	
Non-Repetitive Maximum Avalanche current	I _{AS}	36	A	Note*1
Non-Repetitive Maximum Avalanche Energy	E _{AS}	830	mJ	Note*2
Peak Diode Recovery dV/dt	dV/dt	4.7	kV/μs	Note*3
Peak Diode Recovery di/dt	-di/dt	100	A/μs	Note*4
Maximum Power Dissipation	P _D	570	W	
Operating and Storage Temperature range	T _{ch}	150	°C	
	T _{stg}	-55 to +150	°C	

Note*1 : T_{ch} ≤ 150°C, See Fig.1 and Fig.2

Note*2 : Starting T_{ch}=25°C, L=1169μH, V_{CC}=60V, R_G=50Ω, See Fig.1 and Fig.2

E_{AS} limited by maximum channel temperature and avalanche current.

See to Avalanche Energy graph of page 5

Note*3 : IF ≤ -I_D, -di/dt=100A/μs, V_{CC} ≤ BV_{DSS}, T_{ch} ≤ 150°C

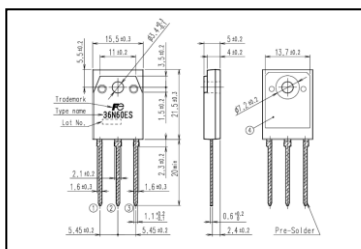
Note*4 : IF ≤ -I_D, dV/dt=4.7kV/μs, V_{CC} ≤ BV_{DSS}, T_{ch} ≤ 150°C

■ Electrical Characteristics at Tc=25°C(unless otherwise specified)

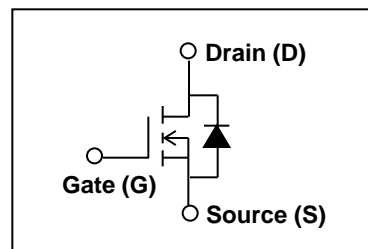
Static Ratings

Description	Symbol	Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV _{DSS}	I _D =1mA V _{GS} =0V	600	—	—	V
	BV _{DSX}	I _D =1mA V _{GS} =-30V	600	—	—	V
Gate Threshold Voltage	V _{GS(th)}	I _D =250μA V _{DS} = V _{GS}	3.7	4.2	4.7	V
Zero Gate Voltage Drain current	I _{DSS}	V _{DS} = 600V V _{GS} =0V Ta=25°C	—	0.7	10	μA
		V _{DS} = 480V V _{GS} =0V Ta=125°C	—	25	250	
Gate-Source Leakage current	I _{GSS}	V _{GS} =30V V _{DS} = 0V	—	10	100	nA
Drain-Source On-State Resistance	R _{DS(on)}	I _D =18A V _{GS} =10V	—	137	160	mΩ

■ Outline Drawings [mm]



■ Equivalent circuit schematic



Dynamic Ratings

Description	Symbol	Conditions	Min.	Typ.	Max.	Unit
Forward Transconductance	g_{fs}	$I_D=18A$ $V_{DS}=25V$	15	—	—	S
Input Capacitance	C_{iss}	$V_{DS}=25V$ $V_{GS}=0V$ $f=1MHz$	—	6000	—	pF
Output Capacitance	C_{oss}		—	650	—	
Reverse Transfer Capacitance	C_{rss}		—	30	—	
Turn-On Time	$t_{d(on)}$	$V_{CC}=300V, V_{GS}=10V$ $I_D=18A, R_G=10\Omega$ See Fig.3 and Fig.4	—	58	—	ns
	t_r		—	75	—	
Turn-Off Time	$t_{d(off)}$		—	115	—	
	t_f		—	30	—	
Total Gate Charge	Q_G	$V_{DD}=300V, I_D=36A$ $V_{GS}=10V$ See Fig.5	—	148	—	nC
Gate-Source Charge	Q_{GS}		—	50	—	
Gate-Drain Charge	Q_{GD}		—	60	—	

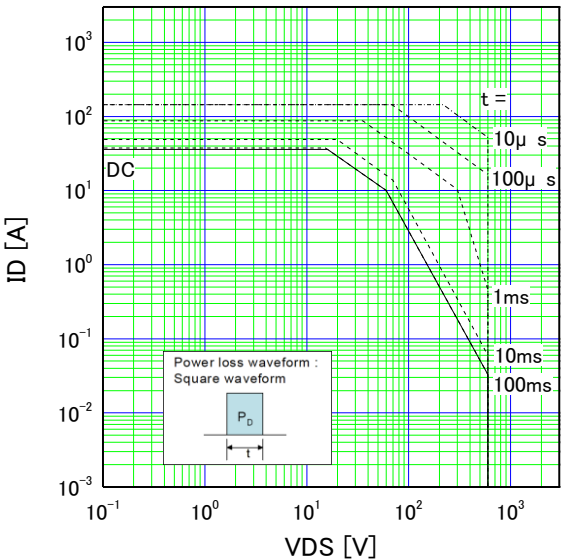
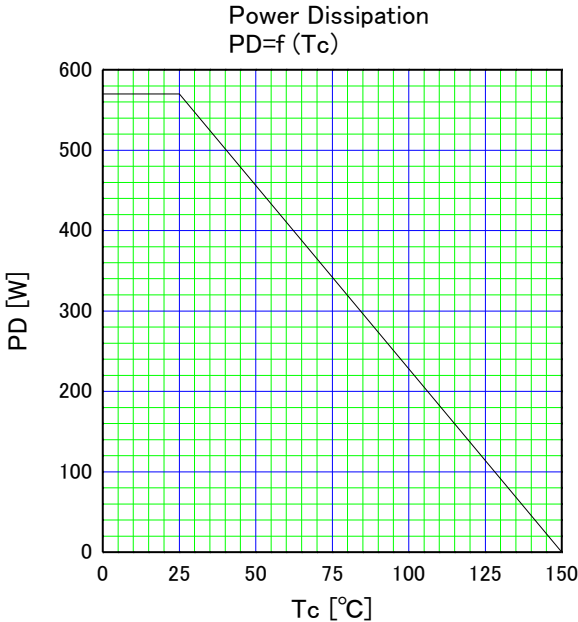
Reverse Ratings

Description	Symbol	Conditions	Min.	Typ.	Max.	Unit
Avalanche Capability	I_{AV}	$L=1169\mu H, T_{ch}=25^\circ C$ See Fig.1 and Fig.2	36	—	—	A
Diode Forward On- Voltage	V_{SD}	$I_F=36A, V_{GS}=0V$ $T_{ch}=25^\circ C$	—	1.10	1.5	V
Reverse Recovery Time	t_{rr}	$I_F=36A, V_{GS}=0V$ $-di/dt=100A/\mu s$ $T_{ch}=25^\circ C$	—	920	—	ns
Reverse Recovery Charge	Q_{rr}		—	22	—	μC

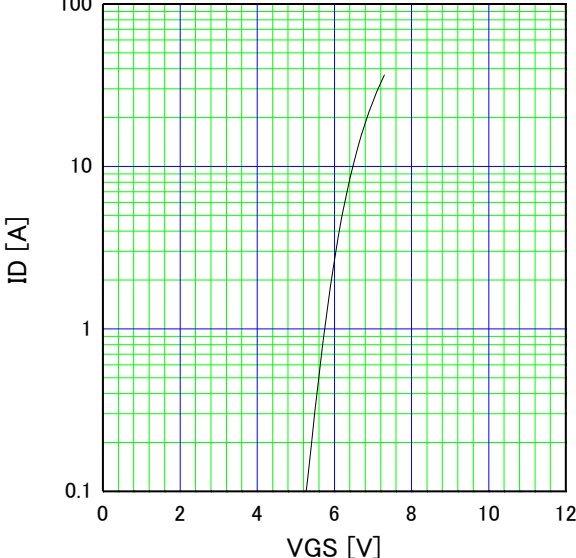
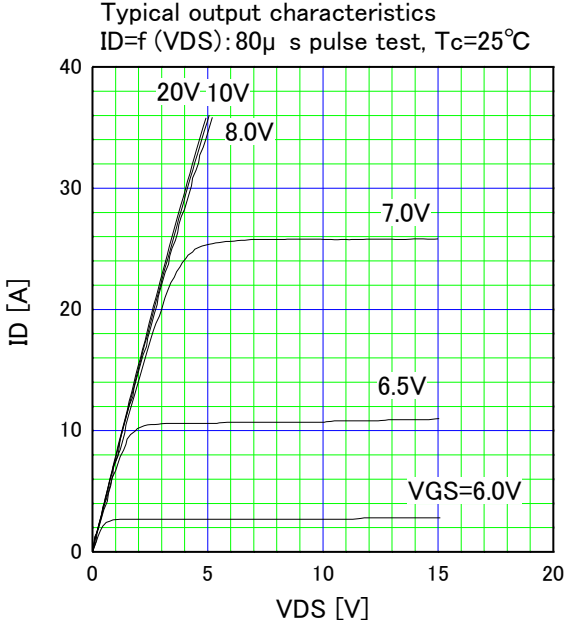
■ Thermal Characteristics

Description	Symbol	Min.	Typ.	Max.	Unit
Cannel to Case	$R_{th(ch-c)}$	—	—	0.219	$^\circ C/W$
Cannel to Ambient	$R_{th(ch-a)}$	—	—	50.0	$^\circ C/W$

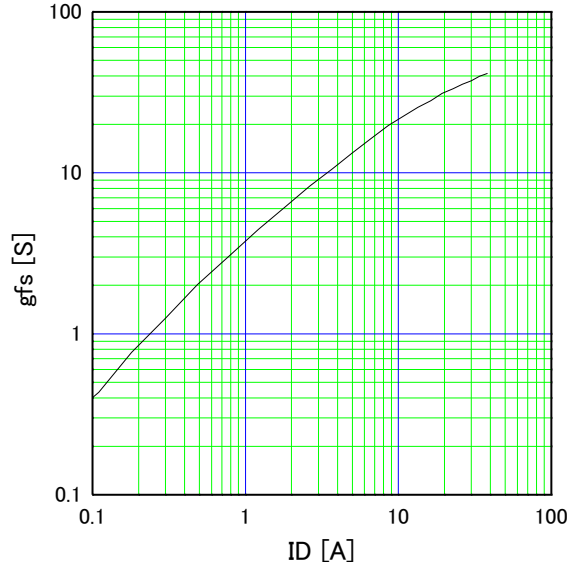
Safe operating area
 $I_D=f(V_{DS})$: Single pulse ($D=0$), $T_c=25^{\circ}\text{C}$



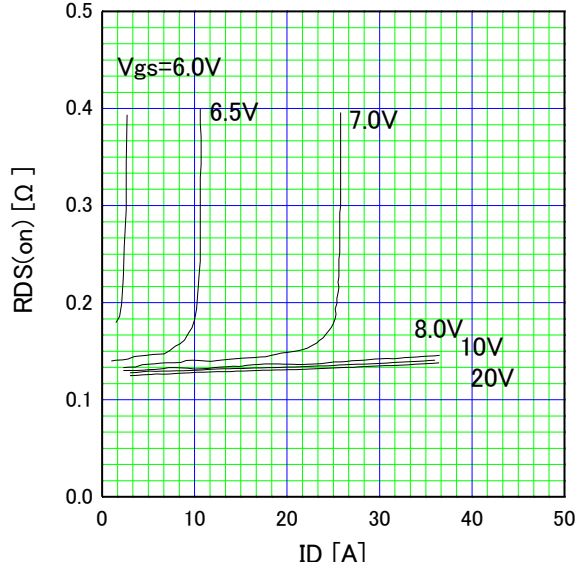
Typical transfer characteristics
 $I_D=f(V_{GS})$: 80µ s pulse test, $V_{DS}=10\text{V}$, $T_{ch}=25^{\circ}\text{C}$



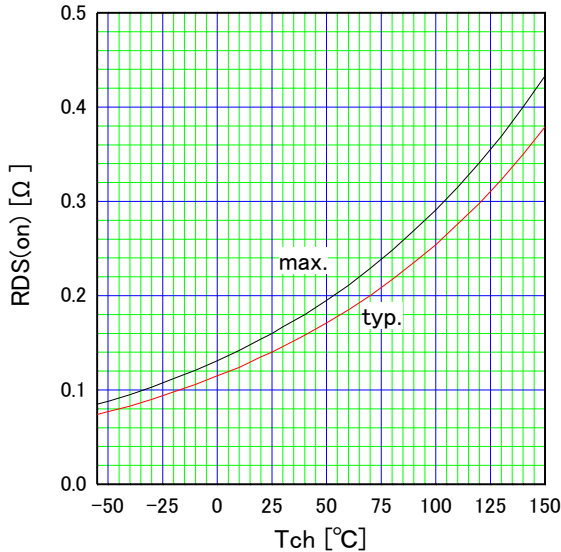
Typical Transconductance
 $g_{fs}=f(I_D)$: 80µ s pulse test, $V_{DS}=25\text{V}$, $T_{ch}=25^{\circ}\text{C}$



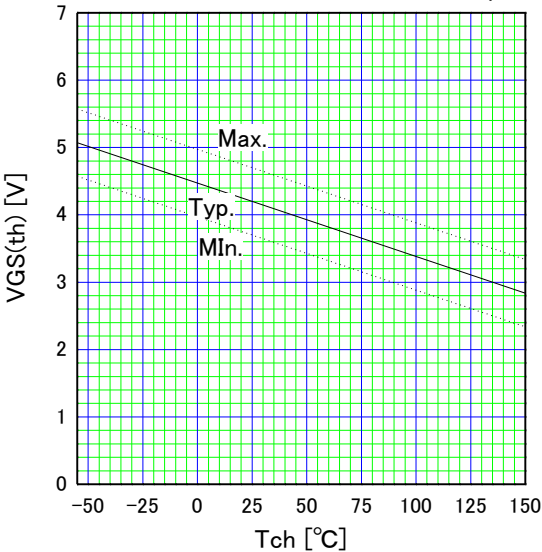
Typical Drain-Source on-State Resistance
 $R_{DS(on)}=f(I_D)$: 80µ s pulse test, $T_{ch}=25^{\circ}\text{C}$



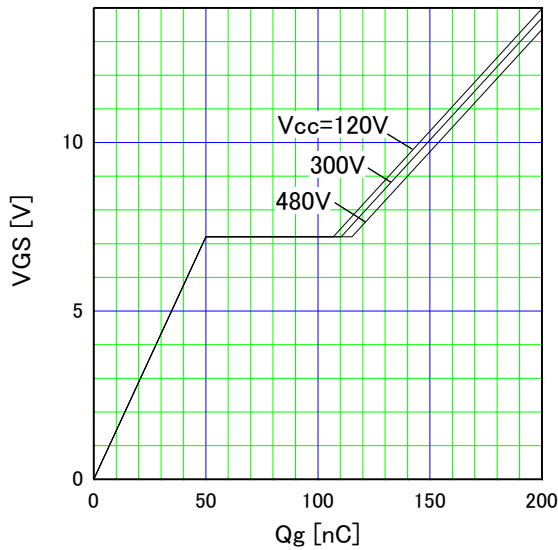
Drain-source on-state resistance
 $R_{DS(on)} = f(T_{ch}) : I_D = 18A, V_{GS} = 10V$



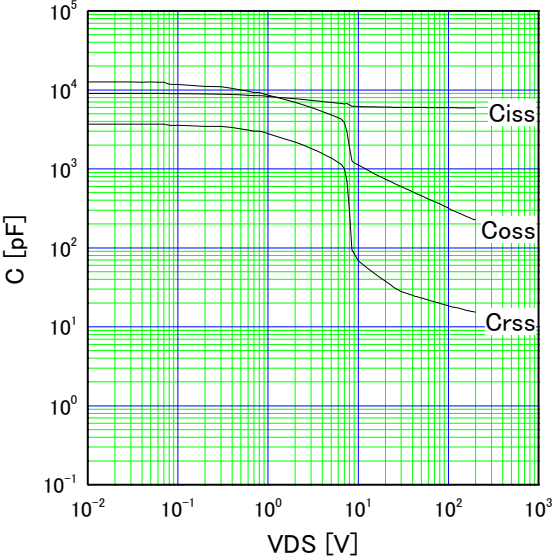
Gate Threshold Voltage vs. T_{ch}
 $V_{GS(th)} = f(T_{ch}) : V_{DS} = V_{GS}, I_D = 250\mu A$



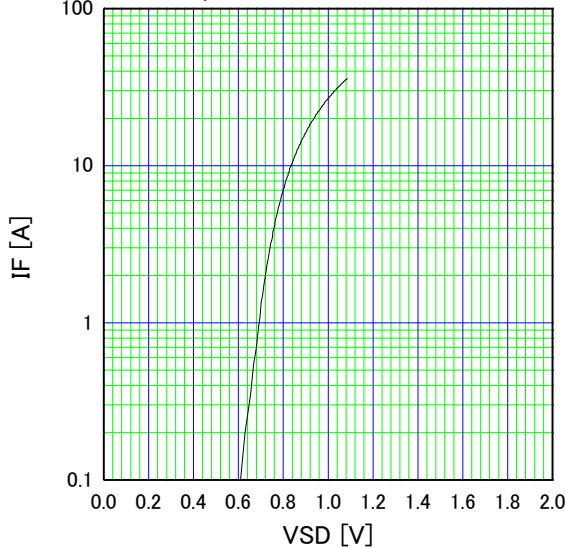
Typical Gate Charge Characteristics
 $V_{GS} = f(Q_g) : I_D = 36A, T_{ch} = 25^{\circ}C$



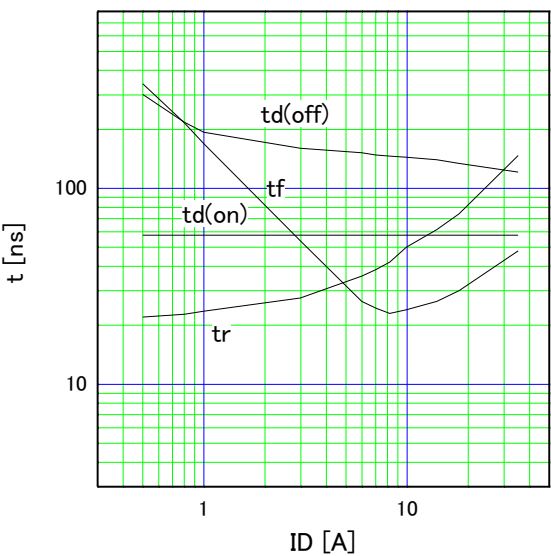
Typical capacitances
 $C = f(V_{DS}) : V_{GS} = 0V, f = 1MHz$



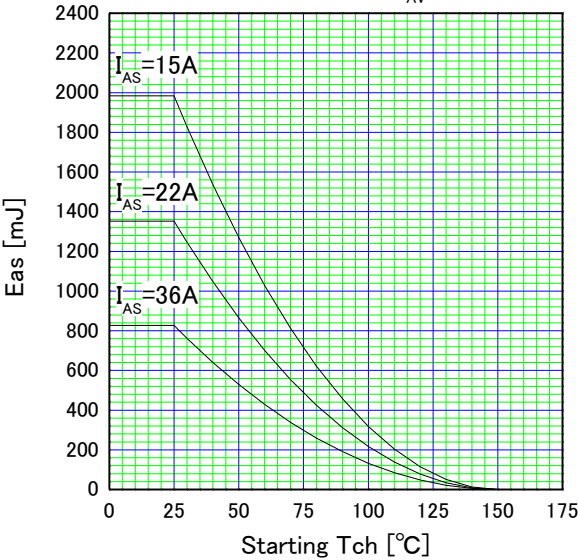
Typical Forward Characteristics of Reverse Diode
 $I_F = f(V_{SD}) : 80\mu s \text{ pulse test}, T_{ch} = 25^{\circ}C$



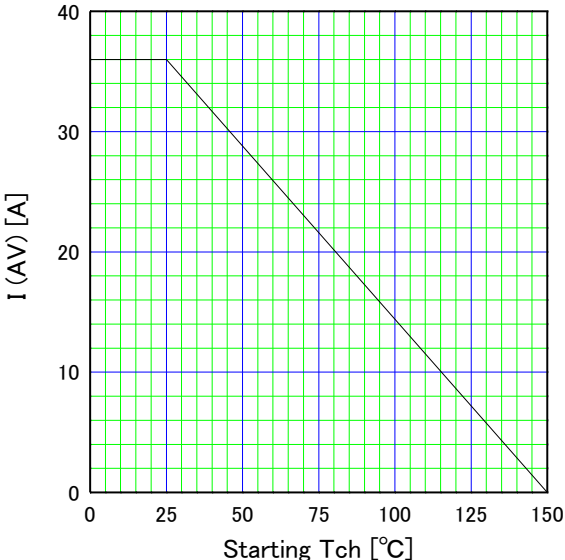
Typical Switching Characteristics vs. I_D
 $t = f(I_D) : V_{CC} = 300V, V_{GS} = 10V, R_G = 10\Omega$



Maximum Avalanche energy vs. starting Tch
 $E_{as}=f(\text{starting Tch}): V_{cc}=60V, I_{AV}\leq 36A, \text{single pulse}$



Maximum Avalanche Current vs. starting Tch
 $I(AV)=f(\text{starting Tch}), \text{single pulse}$



Maximum Transist Thermal Impedance
 $Z_{th(ch-c)}=f(t): D=0$

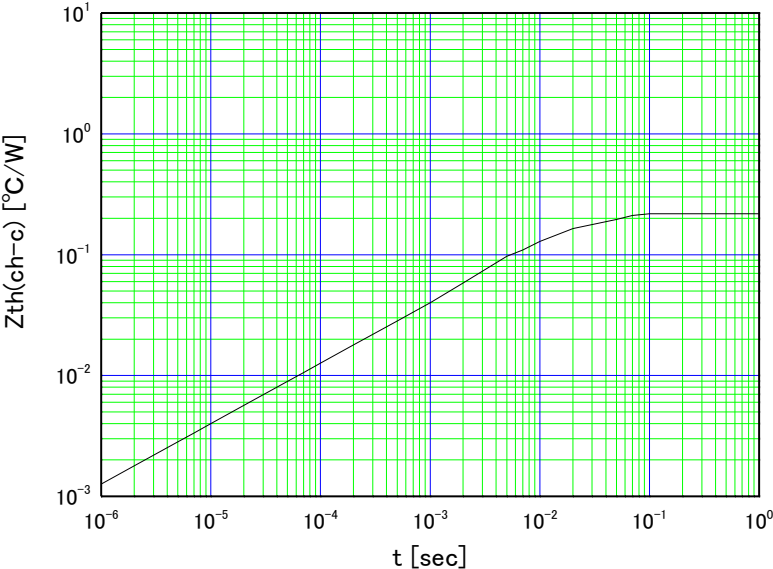


Fig.1 Avalanche Test circuit

Fig.2 Operating waveforms of Avalanche Test

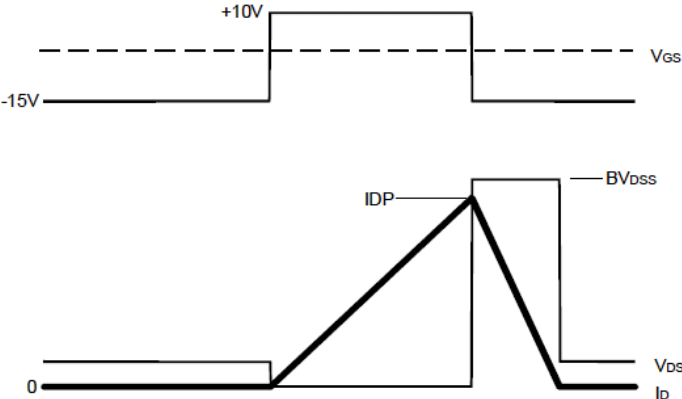
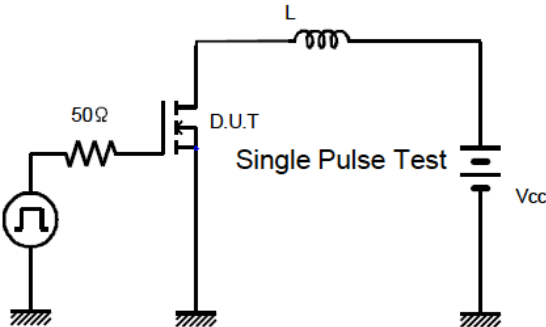


Fig.3 Switching Test circuit

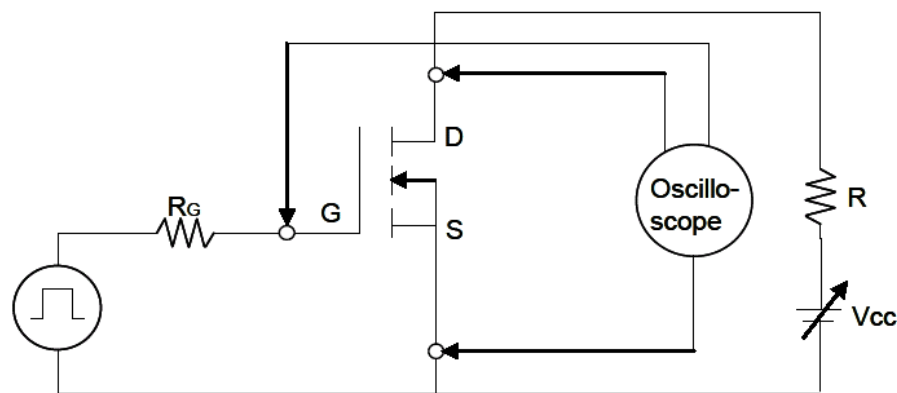


Fig.4 Operating waveform of Switching Test

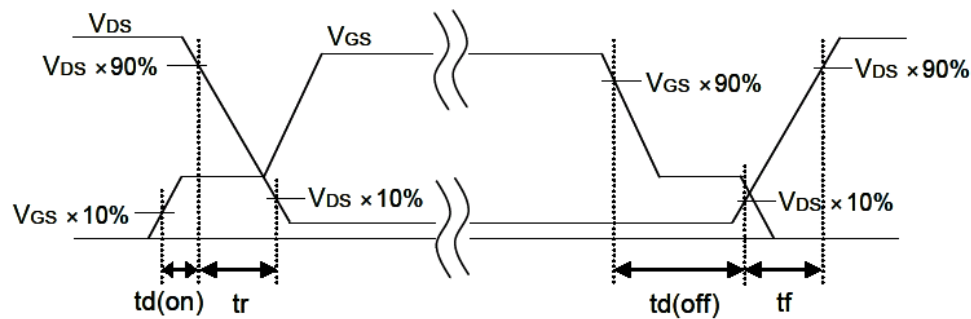


Fig.5 Operating waveform of Gate charge Test

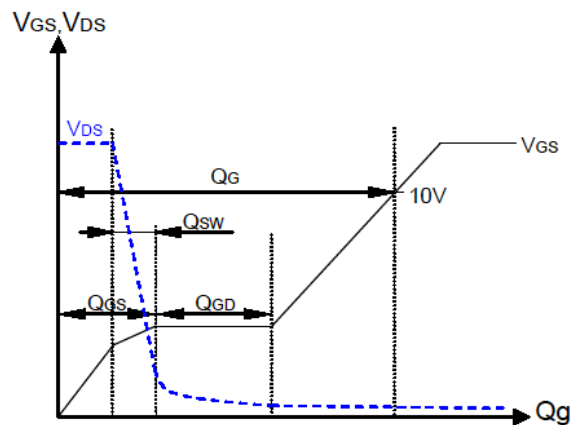
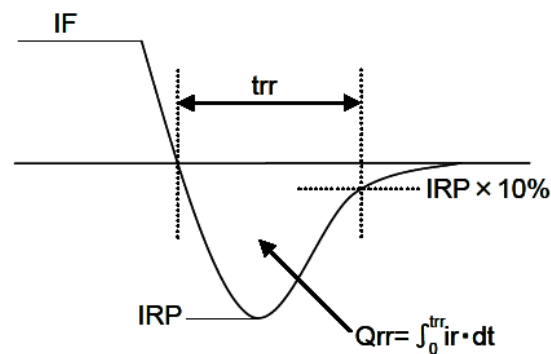


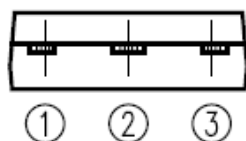
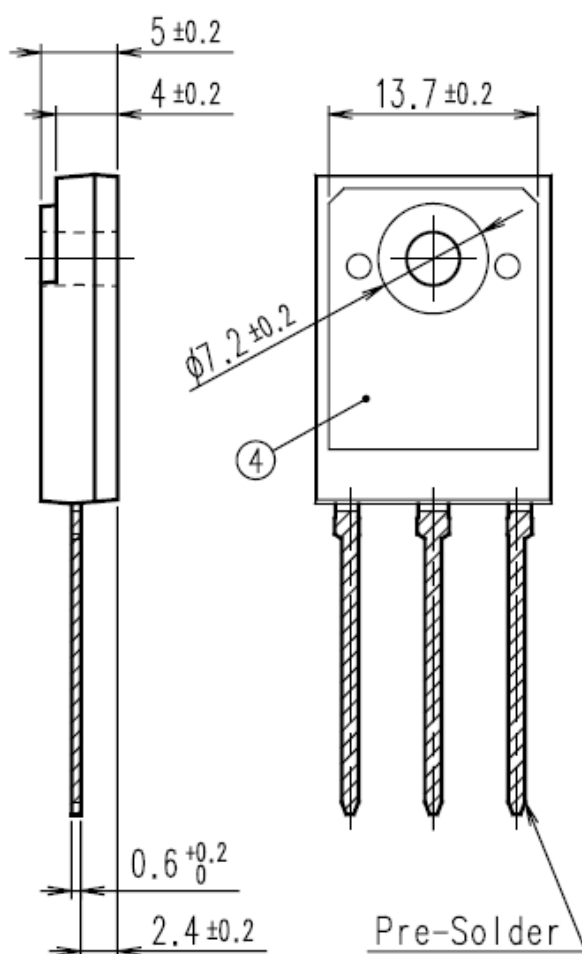
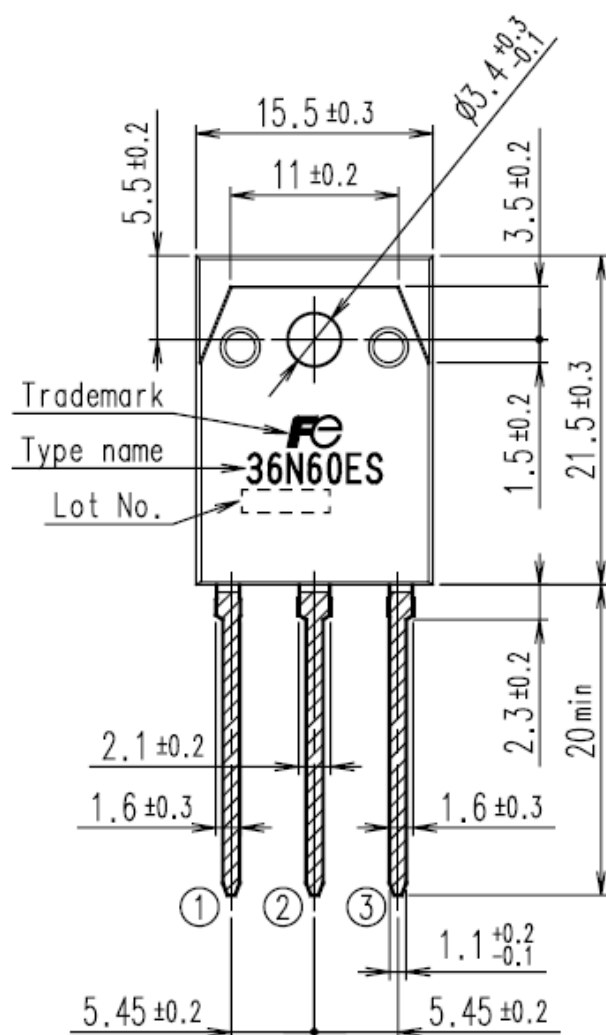
Fig.6 Operating waveform of Body diode Recovery Test



■ Out view

FUJI POWER MOSFET

TYPE : FMY36N60ES



CONNECTION

- ① GATE
② ④ DRAIN
③ SOURCE

JEDEC: TO-247

DIMENSIONS ARE IN MILLIMETERS.

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